Monolithic Accelerometer
With Signal Conditioning

ADXL50*

FEATURES

- Complete Acceleration Measurement System on a Single Monolithic IC
- Full-Scale Measurement Range: ±50 g
- Self-Test on Digital Command
- +5 V Single Supply Operation
- Sensitivity Precalibrated to 19 mV/g
- Internal Buffer Amplifier for User Adjustable Sensitivity and Zero-g Level
- Frequency Response: DC to 10 kHz
- Post Filtering with External Passive Components
- High Shock Survival: >2000 g Unpowered
- Other Versions Available: ADXL05 (±5 g)

GENERAL DESCRIPTION

The ADXL50 is a complete acceleration measurement system on a single monolithic IC. Three external capacitors and a +5 volt power supply are all that is required to measure accelerations up to ±50 g. Device sensitivity is factory trimmed to 19 mV/g, resulting in a full-scale output swing of ±0.95 volts for a ±50 g applied acceleration. Its zero g output level is +1.8 volts.

A TTL compatible self-test function can electrostatically deflect the sensor beam at any time to verify device functionality.

For convenience, the ADXL50 has an internal buffer amplifier with a full 0.25 V to 4.75 V output range. This may be used to set the zero-g level and change the output sensitivity by using external resistors. External capacitors may be added to the resistor network to provide 1 or 2 poles of filtering. No external active components are required to interface directly to most analog-to-digital converters (ADCs) or microcontrollers.

The ADXL50 uses a capacitive measurement method. The analog output voltage is directly proportional to acceleration, and is fully scaled, referenced and temperature compensated, resulting in high accuracy and linearity over a wide temperature range. Internal circuitry implements a forced-balance control loop that improves accuracy by compensating for any mechanical sensor variations.

The ADXL50 is powered from a standard +5 V supply and is robust for use in harsh industrial and automotive environments and will survive shocks of more than 2000 g unpowered.

The ADXL50 is available in a hermetic 10-pin TO-100 metal can, specified over the 0°C to +70°C commercial and -40°C to +85°C industrial temperature ranges. Contact factory for availability of devices specified for operation over the -40°C to +105°C automotive temperature range.

*Patents pending.

REV. B

Information furnished by Analog Devices is believed to be accurate and reliable. However, no responsibility is assumed by Analog Devices for its use, nor for any infringements of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of Analog Devices.
## ADXL50—SPECIFICATIONS

\( (T_A = T_{MIN} \ to \ T_{MAX}, \ T_A = +25°C \ for \ J \ Grade \ Only, \ V_S = +5 \ V, \ \@ \ \text{Acceleration} = 0 \ g, \)

### Parameter Conditions Min ADXL50/A Typ Max Units

<table>
<thead>
<tr>
<th><strong>SENSOR INPUT</strong></th>
<th><strong>Conditions</strong></th>
<th><strong>Min</strong></th>
<th><strong>ADXL50/A</strong></th>
<th><strong>Typ</strong></th>
<th><strong>Max</strong></th>
<th><strong>Units</strong></th>
</tr>
</thead>
<tbody>
<tr>
<td>Measurement Range</td>
<td>Guaranteed Full Scale</td>
<td>-50</td>
<td>0.2</td>
<td>+50</td>
<td>g</td>
<td></td>
</tr>
<tr>
<td>Nonlinearity</td>
<td>Best Fit Straight Line, 50 g FS</td>
<td>±1</td>
<td>% of FS</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Alignment Error(^1)</td>
<td></td>
<td>±2</td>
<td>Degrees</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Transverse Sensitivity(^2)</td>
<td></td>
<td></td>
<td>%</td>
<td></td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th><strong>SENSITIVITY</strong></th>
<th><strong>Conditions</strong></th>
<th><strong>Min</strong></th>
<th><strong>ADXL50/A</strong></th>
<th><strong>Typ</strong></th>
<th><strong>Max</strong></th>
<th><strong>Units</strong></th>
</tr>
</thead>
<tbody>
<tr>
<td>Initial Sensitivity at ( V_{PR} )</td>
<td>+25°C</td>
<td>16.1</td>
<td>19.0</td>
<td>21.9</td>
<td>mV/g</td>
<td></td>
</tr>
<tr>
<td>Temperature Drift(^3)</td>
<td>0.75/1.0</td>
<td></td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th><strong>ZERO g BIAS LEVEL</strong></th>
<th><strong>Conditions</strong></th>
<th><strong>Min</strong></th>
<th><strong>ADXL50/A</strong></th>
<th><strong>Typ</strong></th>
<th><strong>Max</strong></th>
<th><strong>Units</strong></th>
</tr>
</thead>
<tbody>
<tr>
<td>Initial Offset vs. Temperature(^3)</td>
<td></td>
<td>1.55/1.60</td>
<td>1.80</td>
<td>2.05/2.00</td>
<td>V</td>
<td></td>
</tr>
<tr>
<td>vs. Supply ( V_s = 4.75 \ V \ to \ 5.25 \ V )</td>
<td></td>
<td>10</td>
<td>32</td>
<td></td>
<td>mV/V</td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th><strong>NOISE PERFORMANCE</strong></th>
<th><strong>Conditions</strong></th>
<th><strong>Min</strong></th>
<th><strong>ADXL50/A</strong></th>
<th><strong>Typ</strong></th>
<th><strong>Max</strong></th>
<th><strong>Units</strong></th>
</tr>
</thead>
<tbody>
<tr>
<td>Voltage Noise Density at ( V_{PR} ) ( BW = 10 \ Hz \ to \ 1 \ kHz )</td>
<td>6.6</td>
<td>12</td>
<td>mg/\sqrt{Hz}</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Noise in 100 Hz Bandwidth</td>
<td>66</td>
<td></td>
<td>mg rms</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Noise in 1 Hz Bandwidth</td>
<td>20</td>
<td></td>
<td>mg rms</td>
<td></td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th><strong>FREQUENCY RESPONSE</strong></th>
<th><strong>Conditions</strong></th>
<th><strong>Min</strong></th>
<th><strong>ADXL50/A</strong></th>
<th><strong>Typ</strong></th>
<th><strong>Max</strong></th>
<th><strong>Units</strong></th>
</tr>
</thead>
<tbody>
<tr>
<td>( C_1 = 0.022 \ \mu F ) (See Figure 22)</td>
<td>800</td>
<td>1300</td>
<td>kHz</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>( C_1 = 0.0068 \ \mu F )</td>
<td>10</td>
<td>24</td>
<td>kHz</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Sensor Resonant Frequency</td>
<td></td>
<td></td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th><strong>SELF-TEST INPUT</strong></th>
<th><strong>Conditions</strong></th>
<th><strong>Min</strong></th>
<th><strong>ADXL50/A</strong></th>
<th><strong>Typ</strong></th>
<th><strong>Max</strong></th>
<th><strong>Units</strong></th>
</tr>
</thead>
<tbody>
<tr>
<td>Output Change at ( V_{PR} )</td>
<td></td>
<td>0.85</td>
<td>-1.00</td>
<td>-1.15</td>
<td>V</td>
<td></td>
</tr>
<tr>
<td>Logic &quot;1&quot; Voltage</td>
<td></td>
<td>2.0</td>
<td></td>
<td></td>
<td>V</td>
<td></td>
</tr>
<tr>
<td>Logic &quot;0&quot; Voltage</td>
<td></td>
<td></td>
<td></td>
<td></td>
<td>V</td>
<td></td>
</tr>
<tr>
<td>Input Resistance To Common</td>
<td></td>
<td>50</td>
<td>80</td>
<td>0.8</td>
<td>kΩ</td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th><strong>+3.4 V REFERENCE</strong></th>
<th><strong>Conditions</strong></th>
<th><strong>Min</strong></th>
<th><strong>ADXL50/A</strong></th>
<th><strong>Typ</strong></th>
<th><strong>Max</strong></th>
<th><strong>Units</strong></th>
</tr>
</thead>
<tbody>
<tr>
<td>Output Voltage</td>
<td></td>
<td>3.400</td>
<td>3.600</td>
<td>V</td>
<td></td>
<td></td>
</tr>
<tr>
<td>Power Supply Rejection</td>
<td></td>
<td></td>
<td></td>
<td></td>
<td>mV/V</td>
<td></td>
</tr>
<tr>
<td>Output Current</td>
<td></td>
<td></td>
<td></td>
<td></td>
<td>μA</td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th><strong>PREAMPLIFIER OUTPUT</strong></th>
<th><strong>Conditions</strong></th>
<th><strong>Min</strong></th>
<th><strong>ADXL50/A</strong></th>
<th><strong>Typ</strong></th>
<th><strong>Max</strong></th>
<th><strong>Units</strong></th>
</tr>
</thead>
<tbody>
<tr>
<td>Voltage Swing</td>
<td></td>
<td>0.25</td>
<td>80</td>
<td>V</td>
<td></td>
<td></td>
</tr>
<tr>
<td>Current Output</td>
<td></td>
<td></td>
<td></td>
<td></td>
<td>mA</td>
<td></td>
</tr>
<tr>
<td>Capacitive Load Drive</td>
<td></td>
<td>30</td>
<td>100</td>
<td>pF</td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th><strong>BUFFER AMPLIFIER</strong></th>
<th><strong>Conditions</strong></th>
<th><strong>Min</strong></th>
<th><strong>ADXL50/A</strong></th>
<th><strong>Typ</strong></th>
<th><strong>Max</strong></th>
<th><strong>Units</strong></th>
</tr>
</thead>
<tbody>
<tr>
<td>Input Offset Voltage(^6)</td>
<td>Delta from Nominal 1.800 V</td>
<td>±10</td>
<td>±25</td>
<td>mV</td>
<td></td>
<td></td>
</tr>
<tr>
<td>Input Bias Current</td>
<td>DC</td>
<td>5</td>
<td>20</td>
<td>nA</td>
<td></td>
<td></td>
</tr>
<tr>
<td>Open-Loop Gain</td>
<td>80</td>
<td>200</td>
<td>dB</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Unity Gain Bandwidth</td>
<td></td>
<td></td>
<td></td>
<td>kHz</td>
<td></td>
<td></td>
</tr>
<tr>
<td>Unipolar Voltage Swing</td>
<td>( I_{OUT} = ±100 \ \mu A )</td>
<td>0.25</td>
<td></td>
<td>V</td>
<td></td>
<td></td>
</tr>
<tr>
<td>Capacitive Load Drive</td>
<td>1000</td>
<td></td>
<td></td>
<td>pF</td>
<td></td>
<td></td>
</tr>
<tr>
<td>Power Supply Rejection</td>
<td>DC, ( V_S = +4.75 \ V \ to +5.25 \ V )</td>
<td>1</td>
<td>10</td>
<td>mV/V</td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th><strong>POWER SUPPLY</strong></th>
<th><strong>Conditions</strong></th>
<th><strong>Min</strong></th>
<th><strong>ADXL50/A</strong></th>
<th><strong>Typ</strong></th>
<th><strong>Max</strong></th>
<th><strong>Units</strong></th>
</tr>
</thead>
<tbody>
<tr>
<td>Operating Voltage Range</td>
<td></td>
<td>4.75</td>
<td>5.25</td>
<td>V</td>
<td></td>
<td></td>
</tr>
<tr>
<td>Quiescent Supply Current</td>
<td></td>
<td>10</td>
<td>13</td>
<td>mA</td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th><strong>TEMPERATURE RANGE</strong></th>
<th><strong>Conditions</strong></th>
<th><strong>Min</strong></th>
<th><strong>ADXL50/A</strong></th>
<th><strong>Typ</strong></th>
<th><strong>Max</strong></th>
<th><strong>Units</strong></th>
</tr>
</thead>
<tbody>
<tr>
<td>Operating Range ( J )</td>
<td></td>
<td>0</td>
<td>+70</td>
<td>°C</td>
<td></td>
<td></td>
</tr>
<tr>
<td>Specified Performance ( A )</td>
<td></td>
<td>-40</td>
<td>+85</td>
<td>°C</td>
<td></td>
<td></td>
</tr>
<tr>
<td>Automotive Grade(^*)</td>
<td></td>
<td>-40</td>
<td>+125</td>
<td>°C</td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

### NOTES

\(^1\)Alignment error is specified as the angle between the true and indicated axis of sensitivity, (see Figure 2).

\(^2\)Transverse sensitivity is measured with an applied acceleration that is 90° from the indicated axis of sensitivity. Transverse sensitivity is specified as the percent of transverse acceleration that appears at the \( V_{PR} \) output. This is the algebraic sum of the alignment and the inherent sensor sensitivity errors, (see Figure 2).

\(^3\)Specification refers to the maximum change in parameter from its initial at \(+25°C\) to its worst case value at \( T_{MIN} \ to \ T_{MAX} \).

\(^4\)Frequency at which response is 3 dB down from dc response assuming an exact \( C_1 \) value is used. Maximum recommended \( BW \) is 10 kHz using a 0.007 \( \mu F \) capacitor, refer to Figure 22.

\(^5\)Applying logic high to the self-test input has the effect of applying an acceleration of \(-52.6 \ g\) to the ADXL50.

\(^6\)Input offset voltage is defined as the output voltage differential from 1.800 V when the amplifier is connected as a follower (i.e., Pins 9 and 10 tied together). The voltage at Pin 9 has a temperature drift proportional to that of the 3.4 V reference.

\(^*\)Contact factory for availability of automotive grade devices.

All min and max specifications are guaranteed. Typical specifications are not tested or guaranteed. Specifications subject to change without notice.
**ABSOLUTE MAXIMUM RATINGS**

- **Acceleration (Any Axis, Unpowered for 0.5 ms)**: 2000 g
- **Acceleration (Any Axis, Powered for 0.5 ms)**: 500 g
- **Output Short Circuit Duration**
  - \( V_{PR}, V_{OUT}, V_{REF} \) Terminals to Common: Indefinite
- **Operating Temperature**: -55°C to +125°C
- **Storage Temperature**: -65°C to +150°C

*Stresses above those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only; the functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

---

**PACKAGE CHARACTERISTICS**

<table>
<thead>
<tr>
<th>Package</th>
<th>( \theta_J )</th>
<th>( \theta_C )</th>
<th>Device Weight</th>
</tr>
</thead>
<tbody>
<tr>
<td>10-Pin TO-100</td>
<td>130°C/W</td>
<td>30°C/W</td>
<td>5 Grams</td>
</tr>
</tbody>
</table>

**ORDERING GUIDE**

<table>
<thead>
<tr>
<th>Model</th>
<th>Temperature Range</th>
</tr>
</thead>
<tbody>
<tr>
<td>ADXL50JH</td>
<td>0°C to +70°C</td>
</tr>
<tr>
<td>ADXL50AH</td>
<td>-40°C to +85°C</td>
</tr>
</tbody>
</table>

---

**CAUTION**

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the ADXL50 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.

---

**PIN DESCRIPTION**

- **+5 V**: The power supply input pin.
- **C2**: Connection for an external bypass capacitor (nominally 0.022 µF) used to prevent oscillator switching noise from interfering with other ADXL50 circuitry. Please see the section on component selection.
- **C1**: Connections for the demodulator capacitor, nominally 0.022 µF. See the section on component selection for application information.
- **COM**: The power supply common (or “ground”) connection.
- **VREF**: Output of the internal 3.4 V voltage reference.
- **ST**: The digital self-test input. It is both CMOS and TTL compatible.
- **VPR**: The ADXL50 preamplifier output providing an output voltage of 19 mV per g of acceleration.
- **VOUT**: Output of the uncommitted buffer amplifier.
- **VIN–**: The inverting input of the uncommitted buffer amplifier.

---

**CONNECTION DIAGRAM**

- **AXIS OF SENSITIVITY**: Along a line between Pin 5 and the tab. The case of the metal can package is connected to Pin 5 (common).
- **ARROW**: Indicates direction of positive acceleration along axis of sensitivity.
Polarity of the Acceleration Output

The polarity of the ADXL50 output is shown in the Figure 1. When oriented to the earth’s gravity (and held in place), the ADXL50 will experience an acceleration of +1 g. This corresponds to a change of approximately +19 mV at the VPR output pin. Note that the polarity will be reversed to a negative going signal at the buffer amplifier output VOUT, due to its inverting configuration.

Mounting Considerations

There are three main causes of measurement error when using accelerometers. The first two are alignment and transverse sensitivity errors. The third source of error is due to resonances or vibrations of the sensor in its mounting fixture.

Errors Due to Misalignment

The ADXL50 is a sensor designed to measure accelerations that result from an applied force. Because these forces act on the sensor in a vector manner, the alignment of the sensor to the force to be measured may be critical.

The ADXL50 responds to the component of acceleration on its sensitive X axis. Figures 2a and 2b show the relationship between the sensitive “X” axis and the transverse “Z” and “Y” axes as they relate to the TO-100 package.

Figure 2c describes a three dimensional acceleration vector (AXYZ) which might act on the sensor, where AX is the component of interest. To determine AX, first, the component of acceleration in the XY plane (AYX) is found using the cosine law:

\[ A_{XY} = A_{XYZ} \cdot \cos(\theta_{XY}) \]

\[ A_X = A_{XY} \cdot \cos(\theta_{X}) \]

Therefore, typical VPR = 19 mV/g (AXYZ) \cdot (\cos(\theta_{XY}) \cdot \cos(\theta_{X}))

Note that an ideal sensor will react to forces along or at angles to its sensitive axis but will reject signals from its various transverse axes, i.e., those exactly 90° from the sensitive “X” axis. But even an ideal sensor will produce output signals if the transverse signals are not exactly 90° to the sensitive axis. An acceleration that is acting on the sensor from a direction different from the sensitive axis will show up at the ADXL50 output at a reduced amplitude.

<table>
<thead>
<tr>
<th>( \theta_X )</th>
<th>% of Signal Appearing at Output</th>
<th>Output in gs for a 50 g Applied Acceleration</th>
</tr>
</thead>
<tbody>
<tr>
<td>0°</td>
<td>100%</td>
<td>50 (On Axis)</td>
</tr>
<tr>
<td>1°</td>
<td>99.98%</td>
<td>49.99</td>
</tr>
<tr>
<td>2°</td>
<td>99.94%</td>
<td>49.97</td>
</tr>
<tr>
<td>3°</td>
<td>99.86%</td>
<td>49.93</td>
</tr>
<tr>
<td>5°</td>
<td>99.62%</td>
<td>49.81</td>
</tr>
<tr>
<td>10°</td>
<td>98.48%</td>
<td>49.24</td>
</tr>
<tr>
<td>30°</td>
<td>86.60%</td>
<td>43.30</td>
</tr>
<tr>
<td>45°</td>
<td>70.71%</td>
<td>35.36</td>
</tr>
<tr>
<td>60°</td>
<td>50.00%</td>
<td>25.00</td>
</tr>
<tr>
<td>80°</td>
<td>17.36%</td>
<td>8.68</td>
</tr>
<tr>
<td>85°</td>
<td>8.72%</td>
<td>4.36</td>
</tr>
<tr>
<td>87°</td>
<td>5.25%</td>
<td>2.63</td>
</tr>
<tr>
<td>88°</td>
<td>3.49%</td>
<td>1.75</td>
</tr>
<tr>
<td>89°</td>
<td>1.7%</td>
<td>0.85</td>
</tr>
<tr>
<td>90°</td>
<td>0%</td>
<td>0.00 (Transverse Axis)</td>
</tr>
</tbody>
</table>
Table I shows the percentage signals resulting from various θx angles. Note that small errors in alignment have a negligible effect on the output signal. A 1° error will only cause a 0.02% error in the signal. Note, however, that a signal coming 1° off of the transverse axis (i.e., 89° off the sensitive axis) will still contribute 1.7% of its signal to the output. Thus large transverse signals could cause output signals as large as the signals of interest.

Table I may also be used to approximate the effect of the ADXL50’s internal errors due to misalignment of the die to the package. For example: a 1 degree sensor alignment error will allow 1.7% of a transverse signal to appear at the output. In a nonideal sensor, transverse sensitivity may also occur due to inherent sensor properties. That is, if the sensor physically moves due to a force applied exactly 90° to its sensitive axis, then this might be detected as an output signal, whereas an ideal sensor would reject such signals. In every day use, alignment errors may cause a small output peak with accelerations applied close to the sensitive axis but the largest errors are normally due to large accelerations applied close to the transverse axis.

Errors Due to Mounting Fixture Resonances
A common source of error in acceleration sensing is resonance of the mounting fixture. For example, the circuit board that the ADXL50 mounts to may have resonant frequencies in the same range as the signals of interest. This could cause the signals measured to be larger than they really are. A common solution to this problem is to dampen these resonances by mounting the ADXL50 near a mounting post or by adding extra screws to hold the board more securely in place.

When testing the accelerometer in your end application, it is recommended that you test the application at a variety of frequencies in order to ensure that no major resonance problems exist.

GLOSSARY OF TERMS

**Acceleration**: Change in velocity per unit time.

**Acceleration Vector**: Vector describing the net acceleration acting upon the ADXL50 (A_{XYZ}).

**g**: A unit of acceleration equal to the average force of gravity occurring at the earth’s surface, A g is approximately equal to 32.17 feet/s², or 9.807 meters/s².

**Nonlinearity**: The maximum deviation of the ADXL50 output voltage from a best fit straight line fitted to a plot of acceleration vs. output voltage, calculated as a % of the full-scale output voltage (@ 50 g).

**Resonant Frequency**: The natural frequency of vibration of the ADXL50 sensor’s central plate (or “beam”). At its resonant frequency of 24 kHz, the ADXL50’s moving center plate has a peak in its frequency response with a Q of 3 or 4.

**Sensitivity**: The output voltage change per g unit of acceleration applied, specified at the V_{PR} pin in mV/g.

**Sensitive Axis (X)**: The most sensitive axis of the accelerometer sensor. Defined by a line drawn between the package tab and Pin 5 in the plane of the pin circle. See Figures 2a and 2b.

**Sensor Alignment Error**: Misalignment between the ADXL50’s on-chip sensor and the package axis, defined by Pin 5 and the package tab.

**Total Alignment Error**: Net misalignment of the ADXL50’s on-chip sensor and the measurement axis of the application. This error includes errors due to sensor die alignment to the package, and any misalignment due to installation of the sensor package in a circuit board or module.

**Transverse Acceleration**: Any acceleration applied 90° to the axis of sensitivity.

**Transverse Sensitivity Error**: The percent of a transverse acceleration that appears at the V_{PR} output. For example, if the transverse sensitivity is 1%, then a +10 g transverse acceleration will cause a 0.1 g signal to appear at V_{PR} (1% of 10 g). Transverse sensitivity can result from a sensitivity of the sensor to transverse forces or from misalignment of the internal sensor to its package.

**Transverse Y Axis**: The axis perpendicular (90°) to the package axis of sensitivity in the plane of the package pin circle. See Figure 2.

**Transverse Z Axis**: The axis perpendicular (90°) to both the package axis of sensitivity and the plane of the package pin circle. See Figure 2.

Figure 3. 500 g Shock Overload Recovery. Top Trace: ADXL50 Output. Bottom Trace: Reference Accelerometer Output.
ADXL50—Typical Characteristics

Figure 4. Normalized Sensitivity vs. Frequency

Figure 5. Linearity in Percent of Full Scale

Figure 6. –3 dB Bandwidth vs. Temperature at VPR

Figure 7. RMS Noise vs. Value of Demodulator Capacitor, C1

Figure 8. Buffer Amplifier Output Impedance vs. Frequency

Figure 9. Buffer Amplifier Closed-Loop Gain vs. Frequency
Figure 10. Change in Sensitivity vs. Supply Voltage

Figure 11. V<sub>PR</sub> 0 g PSRR vs. Frequency

Figure 12. 0 g Bias Level vs. Temperature

Figure 13. Percent Change in Sensitivity at V<sub>PR</sub> vs. Temperature

Figure 14. +3.4 V REF PSRR vs. Frequency

Figure 15. V<sub>REF</sub> Output and Change in Self-Test Output Swing vs. Temperature
THEORY OF OPERATION

The ADXL50 is a complete acceleration measurement system on a single monolithic IC. It contains a polysilicon surface-micro machined sensor and signal conditioning circuitry. The ADXL50 is capable of measuring both positive and negative acceleration to a maximum level of ±50 g.

Figure 16 is a simplified view of the ADXL50's acceleration sensor at rest. The actual structure of the sensor consists of 42 unit cells and a common beam. The differential capacitor sensor consists of independent fixed plates and a movable "floating" central plate which deflects in response to changes in relative motion. The two capacitors are series connected, forming a capacitive divider with a common movable central plate. A force balance technique counters any impeding deflection due to acceleration and servos the sensor back to its 0 g position.

Figure 16. A Simplified Diagram of the ADXL50 Sensor at Rest

Figure 17 shows the sensor responding to an applied acceleration. When this occurs, the common central plate or "beam" moves closer to one of the fixed plates while moving further from the other. The sensor's fixed capacitor plates are driven differentially by a 1 MHz square wave: the two square wave amplitudes are equal but are 180° out of phase from one another. When at rest, the values of the two capacitors are the same and therefore, the voltage output at their electrical center (i.e., at the center plate) is zero.

When the sensor begins to move, a mismatch in the value of their capacitance is created producing an output signal at the central plate. The output amplitude will increase with the amount of acceleration experienced by the sensor. Information concerning the direction of beam motion is contained in the phase of the signal with synchronous demodulation being used to extract this information. Note that the sensor needs to be positioned so that the measured acceleration is along its sensitive axis.

Figure 17. The ADXL50 Sensor Momentarily Responding to an Externally Applied Acceleration

When the ADXL50 is subjected to an acceleration, its capacitive sensor begins to move creating a momentary output signal. This is signal conditioned and amplified by the demodulator and preamp circuits. The output of the synchronous demodulator drives the preamp—an instrumentation amplifier buffer which is referenced to +1.8 volts. The voltage appearing at the preamp output is fed back to the sensor and electrostatically forces the center plate back to its original center position.

At 0 g the ADXL50 is calibrated to provide +1.8 volts at the VPR pin. With an applied acceleration, the VPR voltage changes to the voltage required to hold the sensor stationary for the duration of the acceleration and provides an output which varies directly with applied acceleration.

The loop bandwidth corresponds to the time required to apply feedback to the sensor and is set by the capacitor C1. The loop response is fast enough to follow changes in g level up to and exceeding 1 kHz. The ADXL50's ability to maintain a flat response over this bandwidth keeps the sensor virtually motionless. This essentially eliminates any nonlinearity or aging effects due to the sensor beam's mechanical spring constant, as compared to an open-loop sensor.

An uncommitted buffer amplifier provides the capability to adjust the scale factor and 0 g offset level over a wide range. An internal reference supplies the necessary regulated voltages for powering the chip and +3.4 volts for external use.
The sensor's tight mechanical spacing allows it to be electrostatically deflected to full scale while operating on a 5 volt supply. A self-test is initiated by applying a TTL "high" level voltage (>+2.0 V) to the ADXL50’s self-test pin which causes the chip to apply a deflection voltage to the beam which moves it an amount equal to –50 g (the negative full-scale output of the device). Note that the ±10% tolerance of the self-test circuit is not proportional to the sensitivity error, see Self-Test section.

The output of the ADXL50’s preamplifier is 1.8 V at 0 g acceleration with an output range of ±0.95 V for ±50 g input, i.e., 19 mV/g. An uncommitted buffer amplifier has been included on-chip to enhance the user’s ability to offset the 0 g signal level and to amplify and filter the signal. Access is provided to both the inverting input and the output of this amplifier via pins V_OUT and V_IN, while the noninverting input is connected internally to +1.8 V reference. The +1.8 V is derived from a resistor divider connected to the 3.4 V reference.

**BASIC CONNECTIONS FOR THE ADXL50**

Figure 19 shows the basic connections needed for the ADXL50 to measure accelerations in the ±50 g range with an output scale factor 40 mV/g corresponding to a 2.5 V 0 g level, a ±2.0 V full-scale swing around 0 g and a 3 dB bandwidth of approximately 1 kHz.

In general, the designer will need to take into account the initial zero g bias when designing circuits. For the ADXL50J this offset is 1.8 V ± 250 mV. When microprocessors and software...
calibration are used and there is a desire to eliminate trim potentiometers, the design should leave room at either supply rail to account for signal swing and or variations in initial zero g bias. For example, in the circuit in Figure 19, the initial zero g bias of ±250 mV will be reflected to the output by the gain of the R3/R1 network, resulting in an output offset of ±526 mV worst case. The offset, combined with a full-scale signal of 50 g, (+2.0 V) will cause the output buffer amplifier to saturate at the supply rail.

The full ±2.25 V output swing of the buffer amplifier can be utilized if the user is able to trim the zero-g bias to exactly 2.5 V. In applications where the full-scale range will be ±25 g or less, a bias trim such as that shown in Figure 20 will almost always be required.

### VARYING THE OUTPUT SENSITIVITY AND 0 g LEVEL USING THE INTERNAL BUFFER AMPLIFIER

The uncommitted buffer amplifier may be used to change the output sensitivity to provide useful full-scale ranges of ±50 g and below. Table I provides recommended resistor values for several standard ranges down to ±10 g. As the full-scale range is decreased, buffer amplifier gain is increased, and the noise contribution as a percentage of full scale will also increase. For all ranges, the signal-to-noise ratio can be improved by reducing the circuit bandwidth, either by increasing the demodulator capacitor, C1, or by adding a post filter using the buffer amplifier.

### Table II. Recommended Resistor Values for Setting the Circuit of Figure 20 to Several Common Full-Scale Ranges

<table>
<thead>
<tr>
<th>FS (g)</th>
<th>Buffer Gain</th>
<th>SF in mV/g</th>
<th>R1</th>
<th>R3</th>
<th>R2</th>
</tr>
</thead>
<tbody>
<tr>
<td>±50.0</td>
<td>2.11</td>
<td>40</td>
<td>49.9 k</td>
<td>105 k</td>
<td>100 k</td>
</tr>
<tr>
<td>±40.0</td>
<td>2.63</td>
<td>50</td>
<td>39.2 k</td>
<td>103 k</td>
<td>100 k</td>
</tr>
<tr>
<td>±30.8</td>
<td>3.42</td>
<td>65</td>
<td>40.2 k</td>
<td>137 k</td>
<td>100 k</td>
</tr>
<tr>
<td>±26.7</td>
<td>3.95</td>
<td>75</td>
<td>28.7 k</td>
<td>113 k</td>
<td>100 k</td>
</tr>
<tr>
<td>±20.0</td>
<td>5.26</td>
<td>100</td>
<td>26.1 k</td>
<td>137 k</td>
<td>100 k</td>
</tr>
<tr>
<td>±10.0</td>
<td>10.53</td>
<td>200</td>
<td>23.7 k</td>
<td>249 k</td>
<td>100 k</td>
</tr>
</tbody>
</table>

Note that the value of resistor R1 should be selected to limit the output current flowing into VPR to less than 25 μA (to provide a safety margin). For a “J” grade device, this current is equal to:

\[
I_{PR} = \frac{(2.05 V - \text{The peak full-scale output voltage at } V_{PR}) - 1.8 V}{R1 \text{ in ohms}}
\]

For ±50 g full-scale range, R1 needs to be 49.9 kΩ or larger in value; but at the lower full-scale g ranges, if the VPR swing is much less, then it is possible to use much lower resistance values. For this table, the circuit of Figure 20 is used, as a 0 g offset trim will be required for most applications. In all cases, it is assumed that the zero-g bias level is 2.5 V with an output span of ±2 V.

Note that for full scales below ±20 g the self-test is unlikely to operate correctly because the VPR pull-down current is not guaranteed to be large enough to drive R1 to the required ~1.0 V swing. In these cases, the self-test command will cause VOUT to saturate at the rail, and it will be necessary to monitor the self-test at VPR. Self-test can remain operational at VPR for all g ranges listed by keeping R1 > 49.9 kΩ, with the subsequent tradeoff that the required values for R3 will become very large. The user always has the option of adding external gain and filtering stages after the ADXL50 to make lower full-scale ranges.

### Measuring Full-Scale Accelerations Less than ±5 g

Applications, such as motion detection, and tilt sensing, have signal amplitudes in the 1 g to 2 g range. Although designed for higher full-scale ranges, the ADXL50 may be adapted for use in low g applications; the two main design considerations are noise and 0 g offset drift (BH, KH grades recommended).

At its full 1 kHz bandwidth, the ADXL50 will typically exhibit 1 g p-p of noise. With ±50 g accelerations this is generally not a problem, but at a ±2 g full-scale level the signal-to-noise ratio will be very poor. However, reducing the bandwidth to 100 Hz or less considerably improves the S/N ratio. Figure 25 shows the relationship between ADXL50 bandwidth and noise.

The ADXL50 exhibits offset drifts that are typically 0.02 g per °C but which may be as large as 0.1 g per °C. With the buffer amplifier configured for a 2 g full scale, the ADXL50 will typically drift 1/2 of its full-scale range with a 50°C increase in temperature.

There are several cures for offset drift. If a dc response is not required, for example in motion sensing or vibration measurement applications, consider ac coupling the acceleration signal to remove the effects of offset drift. See the section on ac coupling.

Periodically recalibrating the accelerometer’s 0 g level is another option. Autozero or long term averaging can be used to remove long term drift using a microprocessor or the autozero circuit of Figure 29. Be sure to keep the buffer amplifier’s full-scale output range much larger than the measurement range to allow for the 0 g level drift.

### Calculating Component Values for Scale Factor and 0 g Signal Level

The ADXL50 buffer’s scale factor is set by –R3/R1 (since the amplifier is in the inverter mode).
As an example, if the desired span is ±2.0 V for a = ±50 g input, then R3/R1 should be chosen such that

\[ R3/R1 = \frac{V_{OUT} \text{ Span}}{V_{PR} \text{ Span}} = 2.00/0.95 = 2.105 \]  

(1)

where \( V_{PR} \) span is the output from the preamplifier and \( V_{OUT} \) span is the buffer amplifier's output, giving

\[ R3 = 2.105 \times R1 \]  

(2)

In noncritical applications, a resistor, R2, may simply be connected between \( V_{IN} \), and common to provide an approximate 0 g offset level (see Figure 19). In this simplified configuration R2 is found using:

\[ R2 = \frac{(1.8 \text{ V} \times R3)/(V_{OUT} @ 0 \text{ g} - 1.8 \text{ V})}{2} \]

When used with a trim potentiometer, as in Figure 20, resistor R2 sets the 0 g offset range and also sets the resolution of the offset trim. A value of 100 kΩ is typical. Increasing R2 above this value makes trimming the offset easier, but may not provide enough trim range to set \( V_{OUT} \) equal to ±2.5 V for all devices.

To provide an output span of ±2.0 V with a 0 g output of ±2.5 V, R1 could be set to the standard value of 49.9 kΩ and from Equation 2, \( R3 = 105 \text{ kΩ} \).

For Figure 20, the circuit transfer function is:

\[ V_{OUT} = \left( \frac{R3}{R1} \frac{(1.8 \text{ V} - V_{PR})}{V_{PR}} + \left( \frac{R3}{R2} \frac{(1.8 \text{ V} - V_{X})}{V_{X}} \right) \right) / 1.8 \text{ V} \]

The summing amplifier configuration allows noninteractive trimming of offset and span. Since \( V_{PR} \) is not always exactly 1.8 V at 0 g, it will contribute to output offset. Therefore, span must be trimmed first, followed by 0 g offset adjustment.

LOAD DRIVE CAPABILITIES OF THE \( V_{PR} \) AND BUFFER OUTPUTS

The \( V_{PR} \) and the buffer amplifier outputs are both capable of driving a load to voltage levels approaching that of the supply rail. However, both outputs are limited in how much current they can supply, affecting component selection.

\( V_{PR} \) Output

The \( V_{PR} \) pin has the ability to source current up to 500 \( \mu \text{A} \) but only has a sinking capability of 30 \( \mu \text{A} \) which limits its ability to drive loads. It is recommended that the buffer amplifier be used in most applications, to avoid loading down \( V_{PR} \). In standard ±50 g applications, the resistor R1 from \( V_{PR} \) to \( V_{IN} \), is recommended to have a value greater than 50 kΩ to reduce loading effects.

Capacitive loading of the \( V_{PR} \) pin should be minimized. A load capacitance between the \( V_{PR} \) pin and common will introduce an offset of approximately 1 mV for every 10 pF of load. The \( V_{PR} \) pin may be used to directly drive an A/D input or other source as long as these sensitivities are taken into account. It is always preferable to drive A/D converters or other sources using the buffer amplifier (or an external op amp) instead of the \( V_{PR} \) pin.

Buffer Amplifier Output

The buffer output can drive a load to within 0.25 V of either power supply rail and is capable of driving 1000 pF capacitive loads. Note that a capacitance connected across the buffer feedback resistor for low-pass filtering does not appear as a capacitive load to the buffer. The buffer amplifier is limited to sourcing or sinking a maximum of 100 \( \mu \text{A} \). Component values for the resistor network should be selected to ensure that the buffer amplifier can drive the filter under worst case transient conditions.

SELF-TEST FUNCTION

The digital self-test input is compatible with both CMOS and TTL signals. A Logic “l” applied to the self-test (ST) input will cause an electrostatic force to be applied to the sensor which will cause it to deflect to the approximate negative full-scale output of the device. Accordingly, a correctly functioning accelerometer will respond by initiating an approximate -1 volt output change at \( V_{PR} \). If the ADXL50 is experiencing an acceleration when the self-test is initiated, the \( V_{PR} \) output will equal the algebraic sum of the two inputs. The output will stay at the self-test level as long as the ST input remains high and will return to the 0 g level when the ST voltage is removed.

A self-test output that varies more than ±10% from the nominal -1.0 V change indicates a defective beam or a circuit problem such as an open or shorted pin or component.

Operating the ADXL50's buffer amplifier at Gains > 2, to provide full-scale outputs of less than ±50 g, may cause the self-test output to overdrive the buffer into saturation. The self-test may still be used in the case, but the change in the output must then be monitored at the \( V_{PR} \) pin instead of the buffer output.

Note that the value of the self-test delta is not an exact indication of the sensitivity (mV/g) of the ADXL50 and, therefore, may not be used to calibrate the device for sensitivity error.

In critical applications, it may be desirable to monitor shifts in the zero-g bias voltage from its initial value. A shift in the 0 g bias level may indicate that the 0 g level has shifted which may warrant an alarm.

POWER SUPPLY DECOUPLING

The ADXL50 power supply should be decoupled with a 0.1 \( \mu \text{F} \) ceramic capacitor from +5 V pin of the ADXL50 to common using very short component leads. For other decoupling considerations, see EMI/RFI section.

OSCILLATOR DECOUPLING CAPACITOR, \( C2 \)

An oscillator decoupling capacitor, \( C2 \), is used to remove 1 MHz switching transients in the sensor excitation signal, and is required for proper operation of the ADXL50. A ceramic capacitor with a minimum value of 0.022 \( \mu \text{F} \) is recommended from the oscillator decoupling capacitor pin to common. Small amounts of capacitor leakage due to a dc resistance greater than 1 MΩ will not affect operation (i.e., a high quality capacitor is not needed here). As with the power supply bypass capacitor, very short component leads are recommended. Although 0.022 \( \mu \text{F} \) is a good typical value, it may be increased for reasons of convenience, but doing this will not improve the noise performance of the ADXL50.
The demodulator capacitor is connected across Pins 2 and 3 to filter the demodulated signal from the sensor beam and to set the bandwidth of the force balance control loop. This capacitor may be used to approximately set the bandwidth of the accelerometer. A capacitor is always required for proper operation.

The frequency response of the ADXL50 exhibits a single pole roll-off response whose nominal 3 dB frequency is set by the following equation:

\[ f_{3\,\text{dB}} = \frac{28.60}{C_1 \text{ in } \mu F} \pm 40\% \]

A nominal value of 0.022 µF is recommended for C1. In general, the design bandwidth should be set 40% higher than the minimum desired system bandwidth due to the ±40% tolerance.

A minimum value of 0.015 µF is required, (over temperature and system life), to prevent device instability or oscillation. The demodulation capacitor should be a low leakage, low drift ceramic type with an NPO (best) or X7R (good) dielectric.

In general, it’s best to use the recommended 0.022 µF capacitor across the demodulator pins and perform any additional low-pass filtering using the buffer amplifier. Using a large demodulator capacitor for low-pass filtering generally results in smaller capacitance values and better overall performance. It is also a convenient and more precise way to set the system bandwidth. Post filtering allows bandwidth to be controlled accurately by component selection and avoids the ±40% demodulation tolerance. Note that signal noise is proportional to the square root of the bandwidth of the ADXL50 and may be a consideration in component selection—see section on noise.

Care should be taken to reduce or eliminate any leakage paths from the demodulator capacitor pins to common or to the +5 V pin. Even a small imbalance in the leakage paths from these pins will result in offset shifts in the zero-g bias level. As an example, an unbalanced parasitic resistance of 30 MΩ from either demodulator pin to ground will result in an offset shift at Vps of approximately 50 mV. Conformal coating of PCB boards with a high impedance material is recommended to avoid leakage problems due to aging or moisture.

Reducing the Average Power Consumption of the ADXL50

The ADXL50 is a versatile accelerometer that can be used in a wide variety of applications. In some battery powered applications, such as shipping recorders, power consumption is a critical parameter. The ADXL50 typically draws 10 mA current from a 5 V power supply which may exceed the power budgeted for the accelerometer.

For such applications, the ADXL50 can be successfully power cycled, where the power is turned on only during the period when data is sampled. Figure 21 illustrates the power-on settling of the ADXL50 during cycling where the output amplifier has a gain of one with no filtering. The settling time constant is approximately 0.12 ms, waiting 1 ms before sampling ensures maximally accurate readings.
ONE POLE POST-FILTERING

Figure 23 shows the ADXL50 buffer amplifier connected to provide one pole post filtering, 0 g offset trimming, and output scaling. The table included with the figure lists practical component values for various full-scale g levels and approximate circuit bandwidths. For bandwidths other than those listed, use the formula:

\[
\text{Capacitor } C_4 \text{ in Farads } = \frac{1}{2\pi \times R_3 \times C_4}
\]

or simply scale the value of capacitor C4 accordingly; i.e., for a ±20 g application with a 50 Hz bandwidth, the value of C4 will need to be twice as large as its 100 Hz value or 0.022 µF × 2 = 0.044 µF. The closest standard value of 0.044 µF should then be used.

TWO POLE POST-FILTERING

Figure 24 shows a circuit which uses the ADXL50’s buffer amplifier to provide two pole post filtering. An AD820 external op amp allows noninteractive adjustment of 0 g offset and scale factor. Component values for the two pole filter were selected to operate the buffer at unity gain with a Q of one.

3dB BW = \frac{1}{2\pi \times R_3 \times C_4}

OBSOLETE
Capacitors C3 and C4 are chosen to provide the desired 3 dB bandwidth. Component values are specified for bandwidths of 10 Hz, 30 Hz, 100 Hz, and 300 Hz. For other 3 dB bandwidths simply scale the capacitor values; i.e., for a 3 dB bandwidth of 20 Hz, divide the 10 Hz bandwidth numbers by 2. The nominal buffer amplifier output will be +1.8 V ± 19 mV/g. Note that the ADXL50's self-test will be fully functional since the buffer amplifier is operated at unity gain and resistor R1 is large. The external op amp offsets and scales the output to provide a +2.5 V ± 2 V output over a wide range of full-scale g levels. The external op amp may be omitted in high g, low gain applications.

**NOISE CONSIDERATIONS**

The output noise of the ADXL50 scales with the square root of its bandwidth. The noise floor may be reduced by lowering the bandwidth of the ADXL50 either by increasing the value of the demodulator capacitor or by adding an external filter. The typical rms noise of the ADXL50, with a bandwidth of 100 Hz and a noise density of 125 µV/√Hz, is estimated as follows:

\[ \text{Noise (rms)} = \left( \frac{125 \, \mu V/\sqrt{Hz}}{100} \right) \sqrt{100} = 1.25 \, \mu V \, \text{rms} \]

Peak-to-peak noise may be estimated with the following equation:

\[ \text{Noise p-p} = (6.6) \times \text{Noise rms} \]

Peak-to-peak noise is thus estimated at 8.25 mV or approximately 0.4 g p-p. The ADXL50 noise is characteristic of white noise. Typical rms and p-p noise for various 3 dB bandwidths is estimated in Figure 25.

![Figure 25. ADXL50 Noise Level and Resolution vs. -3 dB Bandwidth](image)

**AC COUPLING VPR TO BUFFER INPUT**

If a dc response is not required, as in applications such as motion detection or vibration measurement, then ac coupling should be considered. In low g applications, the output voltage change due to acceleration is small compared to the 0 g offset voltage drift. Because ac coupling removes the dc component of the output, the preamp output signal may be amplified considerably without increasing the 0 g level drift. The most effective way to ac couple the ADXL50 is between the preamp output at VPR and the buffer input, VIN, as shown in Figure 26.

![Figure 26. AC Coupling the VPR Output to the Buffer Input](image)

Using this configuration, the system's ac response is now rolled off—at the low frequency end at FL, and at the high frequency end at FH. The normalized frequency response of the system can be seen in Figure 27.

The low frequency roll-off, FL, due to the ac coupling network is:

\[ F_L = 1/(2 \pi R1 C4) \]

The high frequency roll-off FH is determined by the dominant pole of the system which is controlled by either the demodulator capacitor and its associated time-constant or by a dominant post filter.

As a consequence of ac coupling, any constant acceleration component gravity will not be detected (because this too is a dc voltage present at the VPR output). The self-test feature, if used, must be monitored at VPR, rather than at the buffer output.
MINIMIZING EMI/RFI

The architecture of the ADXL50 and its use of synchronous demodulation make the device immune to most electromagnetic (EMI) and radio frequency (RFI) interference. The use of synchronous demodulation allows the circuit to reject all signals except those at the frequency of the oscillator driving the sensor element. However, the ADXL50 does have a sensitivity to RFI that is within ±5 kHz of the internal oscillator’s nominal frequency of 1 MHz. The internal oscillator frequency will exhibit part to part variation in the range of 0.6 MHz to 1.4 MHz.

In general the effect is difficult to notice as the interference must match the internal oscillator within ±5 kHz and must be large in amplitude. For example: a 1 MHz interference signal of 20 mV p-p applied to the ±5 V power supply pin will produce a 200 mV p-p signal at the VPR pin if the internal oscillator and interference signals are matched exactly. If the same 20 mV interference is applied but 5 kHz above or below the internal oscillator’s frequency, the signal level at VPR will only be 20 mV p-p in amplitude.

Power supply decoupling, short component leads (especially for capacitors C1 and C2), physically small (surface mount, etc.) components and attention to good grounding practices all help to prevent RFI and EMI problems. Please consult the factory for applications assistance in instances where this may be of concern.

SELF-CALIBRATING THE ADXL50

If a calibrated shaker is not available, both the 0 g level and scale factor of the ADXL50 may be easily set to fair accuracy by using a self-calibration technique based on the 1 g (average) acceleration of the earth’s gravity. Figure 28 shows how gravity and package orientation affect the ADXL50’s output (TO-100 package shown). Note that the output polarity is that which appears at VPR; the output at VOUT will have the opposite sign. With its axis of sensitivity in the vertical plane, the ADXL50 should register a 1 g acceleration, either positive or negative, depending on orientation. With the axis of sensitivity in the horizontal plane, no acceleration (0 g) should be indicated.

To self-calibrate the ADXL50, place the accelerometer on its side with its axis of sensitivity oriented as shown in “a.” The 0 g offset potentiometer, R1, is then roughly adjusted for midscale: +2.5 V at the buffer output. If the optional scale factor trimming is to be used, it should be adjusted next.

Next, the package axis should be oriented as in “c” (pointing down) and the output reading noted. The package axis should then be rotated 180° to position “d” and the scale factor potentiometer, R1a, adjusted so that the output voltage indicates a change of 2 g’s in acceleration. For example, if the circuit scale factor at the buffer output is 100 mV per g, then the scale factor trim should be adjusted so that an output change of 200 mV is indicated.

Adjusting the circuit’s scale factor will have some effect on its 0 g level so this should be readjusted, as before, but this time checked in both positions “a” and “b.” If there is a difference in the 0 g reading, a compromise setting should be selected so that the reading in each direction is equidistant from +2.5 V. Scale factor and 0 g offset adjustments should be repeated until both are correct. Temporarily placing a capacitor across the buffer amplifier’s feedback resistor will reduce output noise and so aid in trimming the device. Note that, for high full-scale g ranges, ±2 g may be a very small fraction of the full-scale range and device nonlinearity will, therefore, affect the circuit’s high g level accuracy.
Compensating for the 0 g Drift of the ADXL50 Accelerometer

The circuit of Figure 29 provides a linear temperature compensation for the ADXL50. Figure 30 shows the 0 g drift over temperature for a typical ADXL50 with and without this circuit. As shown by Figure 30, the linear portion of the drift curve has been subtracted out. In effect, the curve has been rotated counterclockwise until it is horizontal, leaving just the bow of the curve: that portion which is not linear. As shown by Figure 30, over a +425°C to +70°C range, a 10x reduction in drift is achieved.

The circuit of Figure 29 is essentially a temperature sensor coupled to a Wheatstone bridge. The AD590 provides a 1 µA/°K current output whose voltage scale factor is set by resistor RA. The bridge circuit subtracts out the nominal 298 mV output of the AD590 at +25°C and leaves only the change in temperature, which is what is needed. Without the bridge, the 298 mV room temperature “offset” would “swamp” the much smaller change in output with temperature.

Resistors R5 and R6 form a resistor divider (one half of the bridge) which divides down the ±3.4 V reference output of the ADXL50 to 0.3 V which appears at the noninverting input of the AD820 op amp. Resistors R7 and R8 form the other half of the bridge, and because they have the same ratio as R5 and R6, the op amp will have a +3.4 V output at room temperature.

The circuit of Figure 29 is essentially a temperature sensor coupled to a Wheatstone bridge. The AD590 provides a 1 µA/°K current output whose voltage scale factor is set by resistor RA. The bridge circuit subtracts out the nominal 298 mV output of the AD590 at +25°C and leaves only the change in temperature, which is what is needed. Without the bridge, the 298 mV room temperature “offset” would “swamp” the much smaller change in output with temperature.

Resistors R5 and R6 form a resistor divider (one half of the bridge) which divides down the ±3.4 V reference output of the ADXL50 to 0.3 V which appears at the noninverting input of the AD820 op amp. Resistors R7 and R8 form the other half of the bridge, and because they have the same ratio as R5 and R6, the op amp will have a +3.4 V output at room temperature.

Resistors R5 and R6 form a resistor divider (one half of the bridge) which divides down the ±3.4 V reference output of the ADXL50 to 0.3 V which appears at the noninverting input of the AD820 op amp. Resistors R7 and R8 form the other half of the bridge, and because they have the same ratio as R5 and R6, the op amp will have a +3.4 V output at room temperature.

CALIBRATION PROCEDURE:
AT T_MIN OR LOWER TEMP CAL POINT...
1. SET RB ALL THE WAY TO ONE SIDE.
2. ADJUST RA FOR +3.4V AT TEST POINT “A.”
3. SET RC FOR +2.5V V_OUT (AT PIN 9 OF ADXL50).
4. TEMPORARILY CONNECT A 1.5kΩ RESISTOR BETWEEN THE CENTER OF RB AND GROUND.
5. ADJUST RB FOR +2.5V AT V_OUT.
6. REMOVE THE 1.5KΩ RESISTOR. V_OUT SHOULD NOT CHANGE.
7. GO TO T_MAX OR HIGH TEMP CAL POINT.
8. READJUST RB FOR +2.5V.
9. CALIBRATION COMPLETE.

Figure 29. ADXL50 0 g Drift Compensation Circuit

Figure 30. ADXL50 0 g Drift With and Without the Compensation Circuit of Figure 29